Search Notes

	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/609,377	KANE ET AL.	
Ī	Examiner	Art Unit	
	CUONG H. NGUYEN	3661	

	SEAR	CHED	
Class	Subclass	Date	Examiner
701	19,70	6/20/2007	CHN
73	146	6/20/2007	CHN
702	85	6/20/2007	CHN
324	166	6/20/2007	CHN
104	96,118	1	1
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INTERFERENCE SEARCHED				
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701	19,70	6/23/200	7 CHN	
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702	85			
B61L 25/02 G01C 22/00,02		V		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
WEST/DERWENT frwrd/bkwrd searches on allowable subject matter and closest references	6/22/2007	CHN		
Inventors'names searches	6/22/2007	CHN		
IEEE Xplore	6/22/2007	CHN		